

Search Notes

Application/Control No.

10/670,571

Examiner

TUYEN T. NGUYEN

Applicant(s)/Patent under
Reexamination

OHNO ET AL.

Art Unit

2832

SEARCHED

Class	Subclass	Date	Examiner
336	83, 175, 200, 206- 208, 220- 223	10/15/2005	TTN
<i>updated</i>	<i>—</i>	<i>3/28/06</i>	<i>TTN</i>

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR